IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:

H. MIURA et al.

Serial No.:

Rule 1.53(b) Continuation of U.S. Patent Application

Serial No. 09/893,980 filed June 29, 2001

Filed:

July 25, 2003

For:

SEMICONDUCTOR MEMORY DEVICE

Art Group of Parent:

2818

Examiner of Parent:

Long K. Tran

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.97 AND §1.98

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450 July 25, 2003

Sir:

This Information Disclosure Statement is being filed in accordance with 37 C.F.R. §1.97 along with a Form PTO-1449. This Information Disclosure Statement is being filed simultaneously with the filing of this application.

This application claims priority under 35 U.S.C. §120 from parent Application Nos. 09/893,980, filed June 29, 2001, 08/838,259, filed April 17, 1997, and 08/270,472, filed July 5, 1994. Thus, in accordance with 37 C.F.R. §1.98(d), copies of the references cited or submitted in the parent applications do not need to be filed by the applicant.

It is respectfully requested that this Information Disclosure Statement be considered by the Examiner.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to the deposit account of Antonelli, Terry, Stout & Kraus, Deposit Account No. 01-2135 (500.33045CC3) and please credit any excess fees to such Deposit Account.

Respectfully submitted,

ANTONELLI, TERRY, STOUT & KRAUS, LLP

Ву

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Substitute	e for form 1449A/PTO		-		С	omplete if Known
					Application Number	
	INFORMATION DISCI	LOS	JRE		Filing Date	July 25, 2003
1	STATEMENT BY APP	LIC	ANT		First Named Inventor	MIURA et al.
					Art Unit	Unassigned
	(use as many sheets as ne	cessa	v)		Examiner Name	Unassigned
Sheet	1	of		1	Attorney Docket Number	500.33045CC3

			U.S. PATENT I	DOCUMENTS	
Examiner Initials'	Cite No.1	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
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Examiner Initials'	Cite No. ¹	Foreign Patent Document Country Code ³ –Number ⁴ –Kind Code ⁵ (<i>if known</i>)	Publication Date MM-DD-YYYY	Country	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		JP 3-96249	04/1991	Japan (Abstract only)	-	
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Examiner Signature				Date Considered		

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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